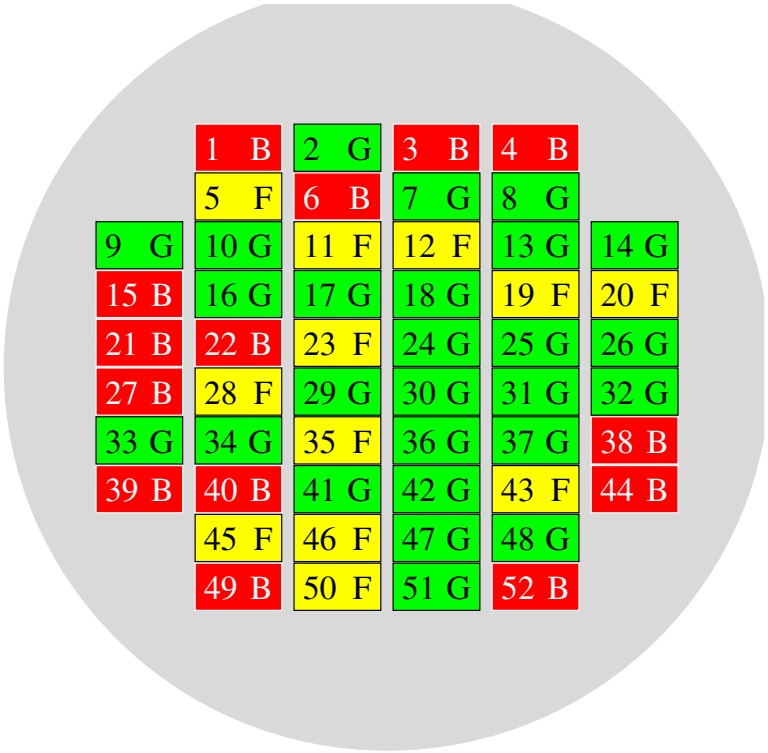
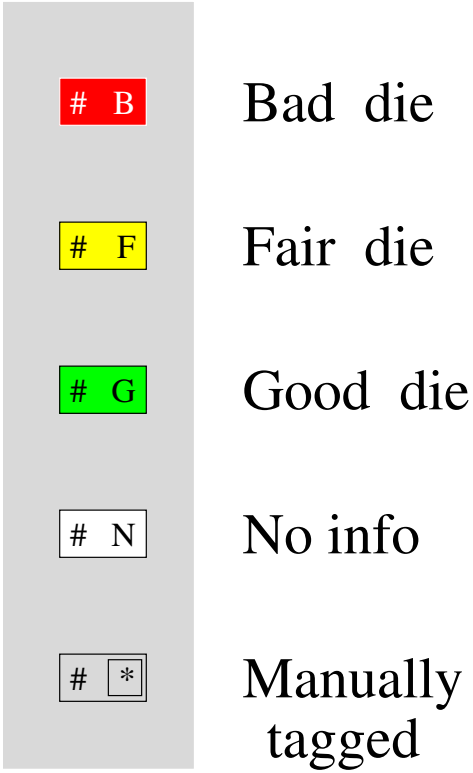
Die quality map for wafer 58 s/n: 21316-07-13

Date: 01/05/99